

Search Notes 	Application/Control No.	Applicant(s)/Patent Under Reexamination
	10761697	SUGA, YUJI
	Examiner San Juan, Martin Jeriko P	Art Unit 2109

SEARCHED

Class	Subclass	Date	Examiner

SEARCH NOTES

Search Notes	Date	Examiner
Consulted with STIC -- EIC2100 via Beale, Terrijor (ASRC)	1/10/2007	MJSJ
Consulted with Art Unit 2132 (Lanier, Benjamin)	1/16/2007	MJSJ
East Search	1/9/2007	MJSJ
Inventor Search thru Bib (eDAN)	1/9/2007	MJSJ

INTERFERENCE SEARCH

Class	Subclass	Date	Examiner